

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership | Publications/Services | Standards | Conferences | Careers/Jobs

IEEE Xplore
RELEASE 1.8Welcome
United States Patent and Trademark Office

» Se

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **2** of **1085387** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

compar* <paragraph> imag* <paragraph> first <par

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard**1 A hybrid fingerprint matcher in memory constrained environments***Krivec, V.; Birchbauer, J.A.; Marius, W.; Bischof, H.;*

Image and Signal Processing and Analysis, 2003. ISPA 2003. Proceedings of the 3rd International Symposium on , Volume: 2 , 18-20 Sept. 2003

Pages:617 - 620 Vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(1408 KB\)\]](#) **IEEE CNF****2 Fingerprint image enhancement using filtering techniques***Greenberg, S.; Aladjem, M.; Kogan, D.; Dimitrov, I.;*

Pattern Recognition, 2000. Proceedings. 15th International Conference on , Volume: 3 , 3-7 Sept. 2000

Pages:322 - 325 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(732 KB\)\]](#) **IEEE CNF** **Print Format**
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore[®]**
RELEASE 1.3Welcome
United States Patent and Trademark Office» **Adva**[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)Welcome to IEEE Xplore[®]

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Try our New Full-text Search Prototype **GO**[Help](#)

1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)

2) Limit your search by using search operators and field codes, if desired.

Example: optical <and> (fiber <or> fibre) <in> ti

3) Limit the results by selecting Search Options.

4) Click Search. See [Search Examples](#)

```
compar* <paragraph> imag*  
<paragraph> first  
<paragraph> second  
<paragraph> fingerprint*
```

Start Search

Clear

Note: This function returns plural and suffixed forms of the keyword(s).

Search operators: <and> <or> <not> <in> [More](#)

Field codes: au (author), ti (title), ab (abstract), jn (publication name), de (index term) [More](#)

Search Options:**Select publication types:**

- ☒ IEEE Journals
- ☒ IEE Journals
- ☒ IEEE Conference proceedings
- ☒ IEE Conference proceedings
- ☒ IEEE Standards

Select years to search:From year: to **Organize search results by:**Sort by: In: orderList Results per page

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

L Number	Hits	Search Text	DB	Time stamp
15	18255	compar\$4 same imag\$4 same first same second	USPAT; US-PGPUB; IBM TDB	2004/10/28 16:54
16	4088	(compar\$4 same imag\$4 same first same second) same position\$4	USPAT; US-PGPUB; IBM TDB	2004/10/28 16:55
17	93	((compar\$4 same imag\$4 same first same second) same position\$4) and fingerprint\$4	USPAT; US-PGPUB; IBM TDB	2004/10/28 16:55